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A Technique For Conducting Experimental And Theoretical Dynamic Research In Design Of Instrument Devices

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Abstract—Background. Investigation of dynamic characteristics of circuit boards in design of instrument devices with the purpose of revealing their vibration relief, determining resonance frequencies and oscillation forms, and also analyzing their vibration resistance under external operational influences, is carried out. In this paper, a technique for determining the locations for installation of measuring devices on circuit boards, including the stage of mathematical modeling of their dynamic state, providing maximum information in the conduct of vibration tests, is proposed. **Materials and methods.** In the article, the circuit boards with hinged electronic components of instrument devices subject to harmonic vibration loading are considered. A technique for performing experimental and theoretical studies, based on preliminary mathematical modeling of the stress-strain state (SSS) of the circuit board under operational dynamic loads is developed. Modeling of the circuit board SSS is performed using the finite element method (FEM) implemented in ANSYS package, taking into account that the circuit board has a layered heterogeneous structure. **Results.** A technique that allows the detection of the most effective locations for measuring devices on circuit boards has been developed to obtain maximum information about SSS of the circuit board and its elements during the vibration testing. **Conclusions.** The conducted numerical studies have shown that the application of the proposed technique at the early stages of designing instrument devices suggests a significant increase in their vibration resistance, helps to reduce time and amount of the performed experimental work, and significantly reduce the economic costs of designing new and upgrading the existing instrument devices.

Keywords—*circuit board, instrument device, mathematical modeling, stress state, technique, vibration test, vibration resistance.*

I. INTRODUCTION

In accordance with the applicable standards, in the development and manufacture of new products, laboratory bench tests are performed for vibratory impact in modes corresponding to the external range of operational influences. In particular, in accordance with GOST 30630.1.1-99, tests are carried out by the 100-1 method in the frequency range ($0.2 f_c$ – $1.5 f_c$), but not more than 2000 Hz. Here, f_c is critical frequency corresponding to the resonance frequency, or the frequency, at which there is a malfunction of the product leading to its failure or the formation and development of defects [1].

To perform vibration tests is important in the development of product design and they are preceded, as a rule, by

mathematical modeling of products' structural elements behavior when vibrating. In this case, the simplest models [2] are most often used, which do not allow getting an adequate picture of the state of the real product. The relevance of the creation of modern techniques for experimental studies of radio-electronic means (REM) and instrument devices is shown in [1, 3].

II. METHODOLOGY OF EXPERIMENTAL AND THEORETICAL RESEARCH

When using the experimental and theoretical research method to study dynamic characteristics of products and their elements, a significant role is played by the location choice of measuring devices (sensors), which register the researched parameter (displacement, acceleration, strain) on the studied object, for example, a circuit board. Location of sensors at points where the registered parameter takes the maximum value should be considered as the most effective. Depending on the goal of experimental studies, allocation of measuring sensors in the areas of the most loaded electrical and radio products (ERP) placed on the circuit boards, or in the most loaded zones of the circuit board, where latent defects are possible, should be considered as the most effective.

Experimental studies should be preceded by mathematical modeling and the analysis of the stress-strain state (SSS) of a circuit board, which allows detecting point location on the circuit board of measuring devices in order to obtain the maximum informative experimental data on the dynamic state of the circuit board. Mathematical models, their analysis and the results of numerical modeling, performed in [3-6], allows proposing a technique for determining the optimal locations for measuring devices to perform dynamic tests in order to obtain the maximum information on the vibration load of the studied object.

A three-dimensional model taking into account the ERP mounting technique on the circuit board [4] should be regarded as an adequate dynamic model for the circuit boards with hinged ERP.

The conducted studies on the numerical modeling of circuit board SSS with ERP has showed that zones in which maximum deflections, strains and accelerations are achieved, as a rule, do not coincide with each other and can occur at different resonant frequencies of the product. In this regard, depending on the studied parameter in the course of SSS preliminary modeling, it is possible to identify the most effective locations of measuring devices installation and to determine the most viable frequency ranges in terms of

vibration resistance and vibration strength for effective conduct of vibration tests.

The basic block diagram of the proposed technique for experimental and theoretical studies is presented in Fig. 1 which consists of the following blocks:

1. Mathematical model of the circuit board is chosen in accordance with the objective of the conducted research [4, 5].

2. Geometrical image of the circuit board model (a, b are dimensions in plan view; h_k is thickness of the circuit board layers).

3. ERP location on the circuit board, taking into account their coordinates, the mounting technique on the circuit board (seam thickness, seam dimensions, ERP overall dimensions).

4. Input of coordinates for the circuit board mounting points (with a diameter of more than 6 mm, it is necessary to take into account the diameter of the fastening screws).

5. Input of physical and mechanical characteristics of the materials of the layers of the heterogeneous structure of the circuit board (elastic moduli E_k , Poisson's ratio μ_k , density ρ_k , the logarithmic damping decrement).

6. Calculation of natural frequencies f_j and selection of frequencies located in the interval of $f_{\min} \leq f_j \leq f_{\max}$, where f_{\min} and f_{\max} are the minimum and maximum frequencies, respectively, which determine the frequency interval in which the tests are planned.

7. Modeling of forms of natural oscillations corresponding to f_j frequencies, and their analysis.

8. Numerical modeling of the studied circuit board model SSS is performed for the chosen forms of natural oscillations at frequencies f_j , and the displacement field $W(x, y)$, equivalent stresses $\sigma_{\text{equ}}(x, y)$ and strains $\varepsilon_{\text{equ}}(x, y)$ over the circuit board surface are determined (x, y are coordinates in the circuit board plane) [4, 5, 6].

9. SSS analysis and the determination of x_i, y_i points coordinates, in which the displacements, stresses and strains take maximum values.

10. Performing adaptation of x_i, y_i coordinates to the circuit board surface and the most loaded ERP. Printout of the optimal coordinates for the allocation of recording devices and the corresponding values of $\max W$, $\max \sigma_{\text{equ}}$, $\max \varepsilon_{\text{equ}}$.

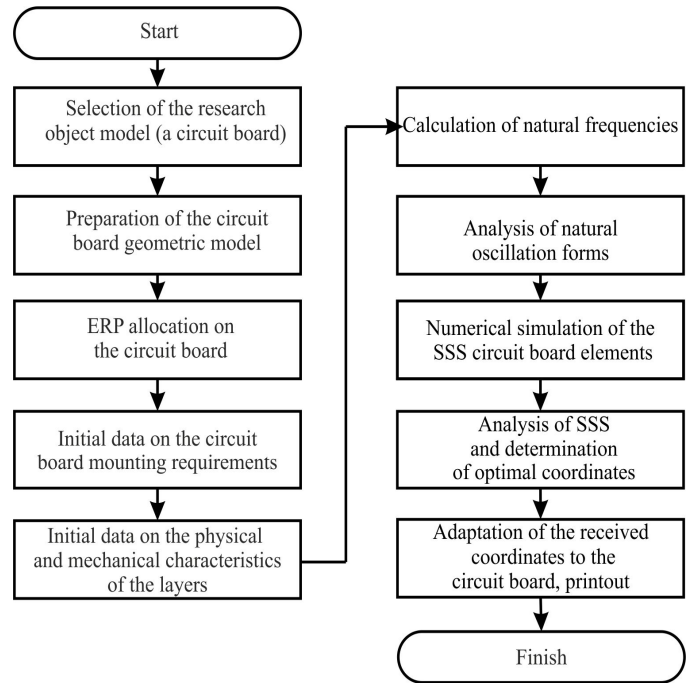


Fig. 1. Block diagram of the technique

The proposed technique for determining the locations of installation of measuring devices is based on the results of a preliminary computational experiment conducted using mathematical models that adequately describe the dynamic state of the studied object during vibration influence in a given frequency range. Knowing frequencies and forms of natural oscillations allows conducting the most accurate determination of the location of the measuring vibrating devices on the circuit board during dynamic tests for the experimental analysis of the vibration relief and vibration strength of the circuit boards.

It is possible to predict the most probable zones of occurrence and development of latent defects (starved seams, solder skips, micro-cracks, etc.) from the analysis of the circuit board SSS and its elements, corresponding to each of their oscillation forms, which allows introducing special additional operations to control the quality of the product at the stage of its manufacturing.

III. PRACTICAL APPLICATION OF THE TECHNIQUE

Let us consider the circuit board with ERP, shown in Fig. 2, as an example of the practical application of the proposed technique, where the scaled ERP dimensions and their location on the circuit board are preserved [6]. To analyze the circuit board SSS, we have numbered the ERP. The circuit board is attached to the base of the electronic unit with five screws.

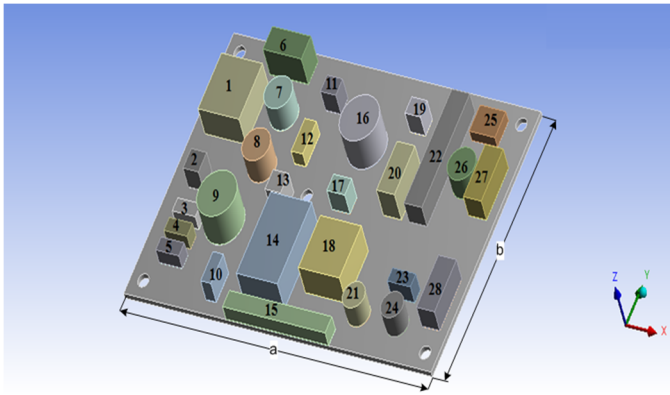


Fig.2. The circuit board

It is accepted to meet the requirements in computer modeling: the sizes of the circuit board should be as follows: $(a \times b) = (120 \times 80) \text{ mm}^2$; $h = 1.5 \text{ mm}$; the circuit board material is fiberglass with elastic modulus of $E = 3 \times 10 \text{ MPa}$; Poisson's ratio is $\mu = 0.22$ and density is $\rho = 2000 \text{ kg/m}^3$, the seam thickness is $h_s = 0.1 \text{ mm}$, the material of seams is tin-lead solder (POS-61); the circuit board is attached to the base with screws with a diameter of 4 mm. The acceleration of $10g$ is directed to the z axis of the circuit board (Fig. 2), and the average value of the logarithmic damping decrement for the circuit board is assumed to be 0.133 .

Table 1 shows the values of the first eight natural frequencies f_j located in the frequency range of $20 \leq f_j \leq 2000$ (Hz) at an ambient temperature in the range of $T = (-60; +125)^\circ\text{C}$.

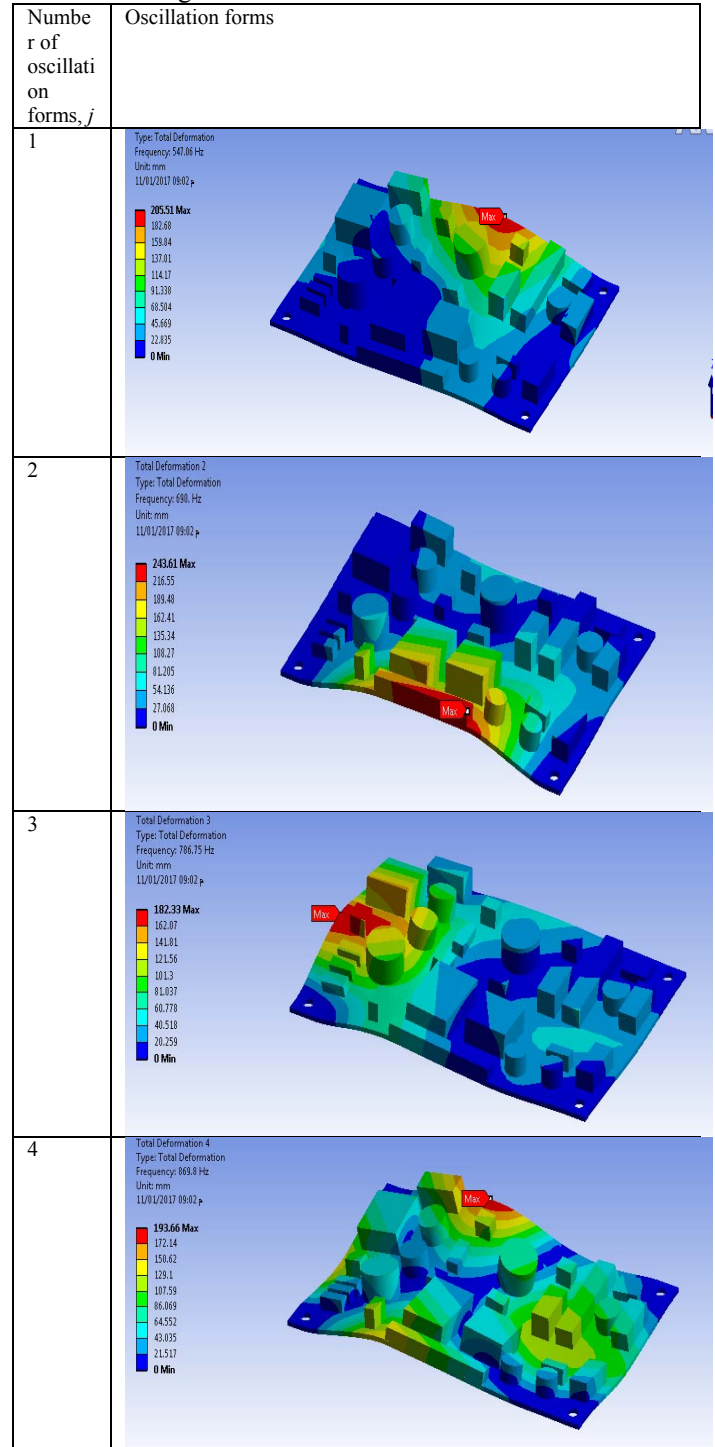
TABLE 1
NATURAL FREQUENCIES f_j OF THE CIRCUIT BOARD

| Frequency f_j , Hz | f_1 | f_2 | f_3 | f_4 | f_5 | f_6 | f_7 | f_8 |
|----------------------|-------|-------|-------|-------|--------|--------|--------|--------|
| $T, ^\circ\text{C}$ | | | | | | | | |
| -60 | 547.1 | 690.0 | 786.8 | 869.8 | 1137.9 | 1554.3 | 1795.1 | 1902.1 |
| 22 | 531.7 | 672.3 | 768.8 | 844.8 | 1107.7 | 1529.7 | 1777.3 | 1871.5 |
| 125 | 511.2 | 648.4 | 743.3 | 812.9 | 1068.3 | 1497.8 | 1753.2 | 1833.1 |

The analysis of results shows that a change of external temperature from -60°C to $+125^\circ\text{C}$ leads to a decrease of the natural frequencies values by $3.8 \dots 7.1\%$, depending on the natural frequency number.

Fig.3. shows the first four forms of the circuit board natural oscillations at the temperature of $T = 22^\circ\text{C}$ where resonances take place. The flags indicate the points at which the circuit board deflections reach the maximum values ($\max W$). The oscillations forms do not change significantly at other temperatures. The amplitude-frequency characteristics (AFC)

of the maximum deflections in the researched frequency range are shown in Fig. 4.

Fig.3. Forms of circuit board oscillations at $T = 22^\circ\text{C}$

The analysis of results shows that the maximum deflection of the circuit board is equal to $\max W = 3.4 \times 10^{-2} \text{ mm}$, and is achieved at $T = 125^\circ\text{C}$ on the second oscillation form (Fig. 3) at a frequency of $f_2 = 648.4 \text{ Hz}$.

If displacement transducers are used during the dynamic tests of the circuit board, they must be installed on the circuit board at the points marked with flags in Fig. 3, where the deflection reaches the maximum values. The AFC analysis (Fig. 4) shows that the most informative is the frequency range

of $0.7 f_2 \leq f_j \leq 1.4 f_2$, i.e. the frequency range $f=(450 \dots 910)$ Hz.

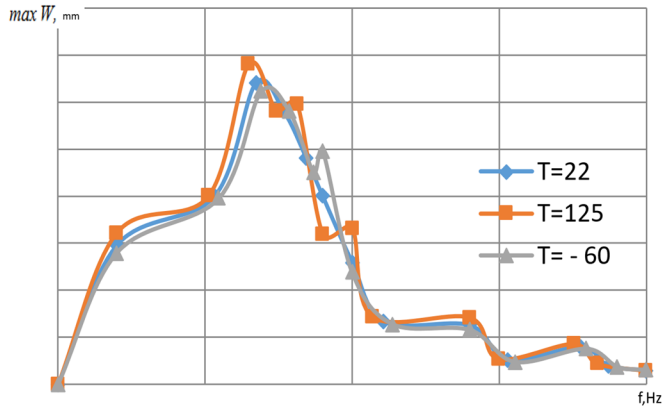


Fig.4. AFC of the circuit board

The circuit board SSS in the studied frequency and temperature range was modeled using von Mises strength criterion. The SSS analysis showed that the most loaded zone of the circuit board is the 13th ERP located near its corner point, not far from the fifth attached point of the circuit board (Fig. 2). The maximum stresses are obtained on the fourth oscillation form at $T=125^\circ\text{C}$ and the frequency $f_4=812.9$ Hz. Change of equivalent stresses σ_{equ} in the zone of the most loaded ERP in the frequency range under various thermal effects is shown in Fig. 5.

Obviously, if tests are carried out on the vibration strength of the studied circuit board, then sensors measuring relative strain (for example, strain gauges) should be placed in the most loaded zone of the circuit board near the 13th ERP. The interval $0.7f_2 \leq f_j \leq 1.4 f_2$, i.e. the frequency range of $f=(570 \dots 1140)$ Hz is the most informative regarding the circuit board SSS.

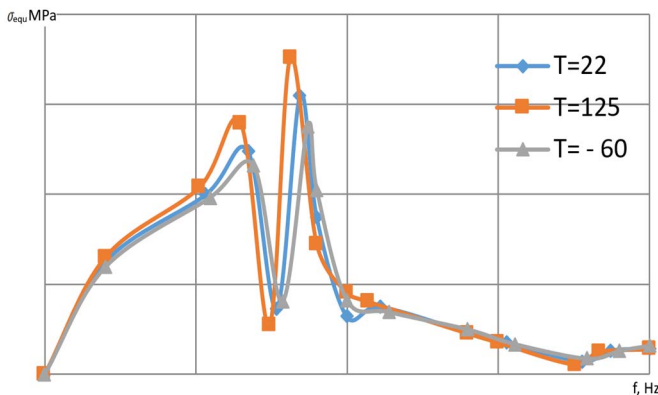


Fig. 5. Changes of σ_{equ} in the 13th ERP zone

It should be noted that a detailed analysis of the simulated circuit board SSS over its entire surface shows that the equivalent stresses do not exceed $\sigma_{\text{equ}} 42.5$ MPa in its remaining zones in the studied thermal and frequency ranges. Consequently, this frequency range is the most informative in terms of the circuit board vibration strength. Vibration testing is recommended at $T=125^\circ\text{C}$.

IV. CONCLUSION

The suggested technique is recommended for practical use

in the early stages of design of structural elements of instrument devices for various purposes to ensure the vibration strength and vibration resistance of devices in real operating conditions. Its application gives the opportunity to shorten the time for designing of new and upgrading the existing instrument devices by reducing the amount of necessary experimental research, and optimizing the accepted design and technological solutions. This leads to a reduction of the economic costs for product designing and upgrading. The analysis of the stress-strain state of structural elements allows us to analyze possible causes of product failures in operation or during testing [7].

The preliminary SSS modeling also allows assigning the optimal modes of technological training of the product, including thermal and vibration effects, to identify possible hidden production defects [8].

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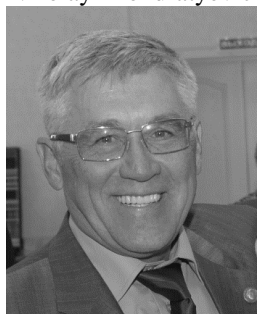
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